

Investigation of Structural, Thermal and High-temperature Piezoelectric Properties of $\text{Ca}_3\text{Ta}(\text{Ga}_{1-x}\text{Al}_x)_3\text{Si}_2\text{O}_{14}$ Crystals Grown by Vertical Bridgman Method

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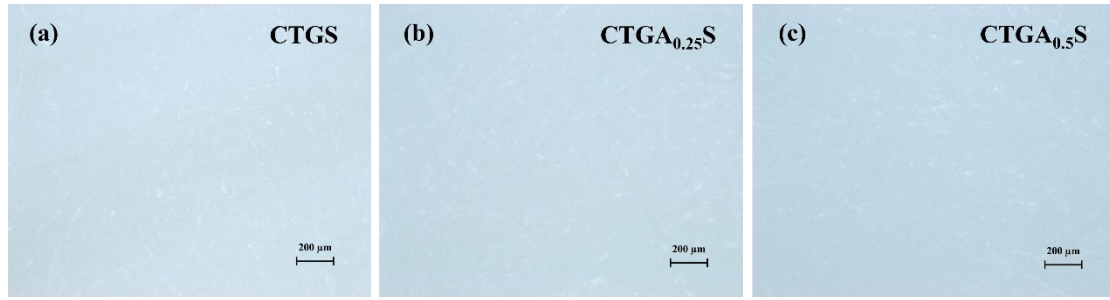


Figure S1 The optical microscopy images of the wafers of (a) CTGS, (b) CTGA_{0.25}S, and (c) CTGA_{0.5}S



Figure S2 (a) Polycrystalline crystal obtained at a lower seeding temperature, (b) cracked crystal formed under a faster cooling rate.